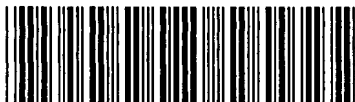


**Search Notes**

Application/Control No.

10/043,047

Examiner

Tse Chen

Applicant(s)/Patent under  
Reexamination

YOO ET AL.

Art Unit

2116

**SEARCHED**

Class	Subclass	Date	Examiner
713	500	6/24/2007	TC
713	600	6/24/2007	TC

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
713	500	6/24/2007	TC
713	600	6/24/2007	TC

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor name	6/24/2007	TC
713/500 and 713/600 with "stub memory"	6/24/2007	TC